"Typically, when Agilent's Manufacturing Test Division introduces a new software revision for its flagship 3070 In-Circuit Tester we only communicate with customers about the major new features. With the release of our new version 5.0 software, in addition to some terrific new capabilities, we have an abundance of enhancements to existing features" according to Marty Leeke, Marketing Product Manager, for the release. "We think our customers will be thrilled to learn about all that's new in 5.0", says Leeke. The newest software for the 3070 includes a whole new platform for the In-System Programming (ISP) of Flash Memory and Programmable Logic Devices. In addition to the new ISP capabilities, version 5.0 includes significant enhancements to Agilent's InterconnectPlus Boundary Scan, Automated Silicon Nails, Access Consultant, Coverage Analyst, AwareTest, and System Diagnostics.

Enhancements to our InterconnectPlus Boundary Scan (BSCAN) program include improvements to system stability that result in more reliable boundary scan tests. Customers who experience ground bounce problems will find our new release more robust in this area. Our BSCAN program has also been updated to include support for IEEE 1149.1 2001 BSDL. Automated Silicon Nails, Agilent's solution for automating boundary scan test development also received a facelift in terms of recognizing boundary scan resources instead of using nail resource allocation. Additionally, Automated Silicon Nails is now supported in our Access Consultant product.

Access Consultant now offers significant "ease-of-use" features for 3070 users. New menus have been introduced that make selection of subsets of nodes, based on node characteristics. Additional reporting features make their debut in our Coverage Analyst product. Connect Check and Polarity Check reports are now included in the already strong reporting capability of Coverage Analyst. Our AwareTest tool has been expanded to include new libraries that will aid users in developing programs incorporating use of the tool. Overall performance of many AwareTest operations have been improved and run significantly faster than before. Rounding-out the feature enhancements in version 5.0 are the improvements to our 3070 System Diagnostics. Overall diagnostic throughput has been improved by up to 50%, depending on the customer's testhead configuration. This translates into much better Mean-Time-to-Repair (MTTR) times on the shop floor, thus minimizing system downtime.

"Our commitment to meeting customer demands is evident in this release", says Leeke. "Many of these product enhancements were driven by direct input from customers through our Customer Responsiveness Initiative. As part of this software release, Agilent incorporated more than 130 enhancements recommended by our customers. This focus on meeting customers' needs is instrumental in the success of the 3070 program."

Additional information on these and other products is as close as your local Agilent representative. Contact us today for more information!